

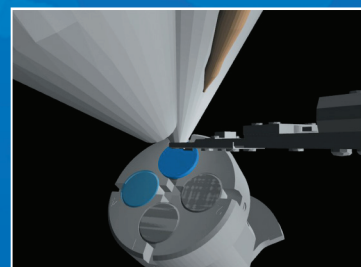
JIB-PS500i

High Performance FIB-SEM from JEOL technologies

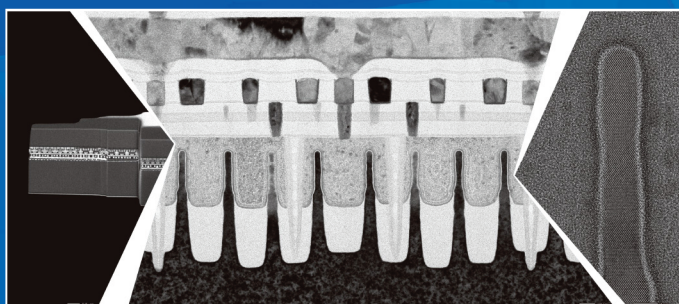
- Automatic TEM sample preparation
- 3D acquisition (imaging, EDS, EBSD)
- New EOS design with dual mode operation
- Check & Go directly from FIB to TEM
- Omniprobe integrated inside GUI



STEMPLING 2



New stage design



Check & Go directly from FIB to TEM



Large specimen chamber



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